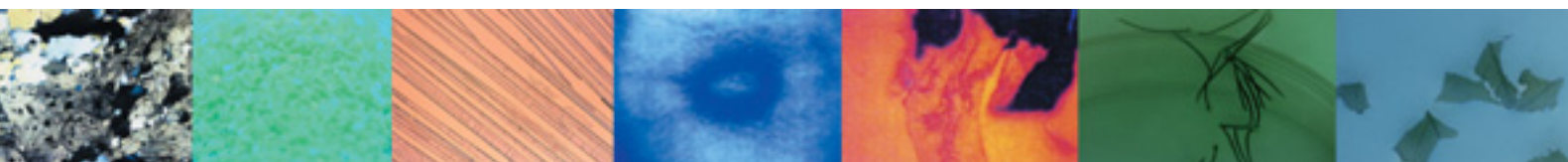
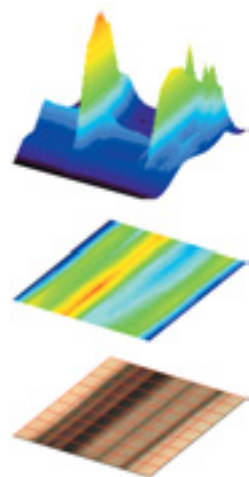


FT-IR Micro-area Analysis IQ Mapping™

JASCO's new FT-IR microscope systems feature an innovative capability for sample analysis, "IQ Mapping". This function enables automated multi-point mapping, line mapping and IR Imaging analyses of a microscopic area with a manual sample stage and a single element detector. The microscope system automatically scans the specified points or area, rapidly collecting a full spectrum of each point without moving the sample stage.

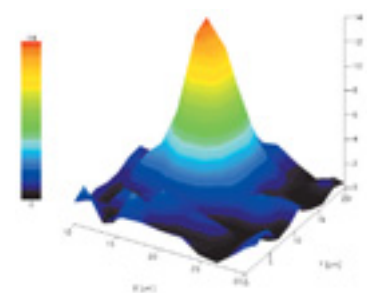
The IQ Mapping function can provide a measurement of a maximum area of 400 μm square using the 16 \times cassegrain objective. The combination of IQ Mapping with the automated XYZ stage provides a wide area analysis capability.



Sampling Flexibility

A wide range of data acquisition modes provides the best solution for almost any type of sample and application.

- **IQ Mapping**
Single point
Multi-point
Line Mapping
Grid Mapping
Micro-ATR Mapping
- **IQ Mapping with automatic X-Y-Z stage**
Wide-area Mapping
Multi-ATR Mapping
- **Linear array detector and rapid scan**
IR Imaging
- **Linear array detector and step scan**
Dynamic Imaging



ATR Mapping using the IQ Mapping function
Sample: silica bead (HPLC packing material)

Colored 3D display of Si-O peak area near 1100 cm^{-1}
Sample: 2 μm Silica bead

Sample compartment microscope for FT-IR

Irtron μ



The Irtron μ sample compartment microscopy system is designed to provide affordable analysis of microscopic samples with the high performance features of an external FT-IR microscope accessory. The Irtron μ offers unprecedented convenience and ease of use in conjunction with the JASCO FT/IR-4000 and 6000 Series FT-IR instruments. The microscope accessory installs into the spectrometer sample compartment in seconds without optical alignment. The state-of-the-art optical design guarantees high throughput for highly sensitive measurements of samples approaching 20 microns.

- Transmittance, reflectance and ATR (option) measurement modes
- DLATGS, MCT or NIR optimized detector
- Five-inch TFT LCD monitor for sample observation
- Optional sampling accessories for liquid and powder samples
- Affordable, easy-to-use microscopy system



Precision Cutting from 10-200 μm

SliceMaster

SliceMaster is a compact, easy to use instrument that can create thin sections by cutting film-type samples.



● Specifications are subject to change without notice.

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JASCO's Next Generation FT-IR Microscopes

Innovation in FT-IR microscopy and imaging systems

IRT-5000

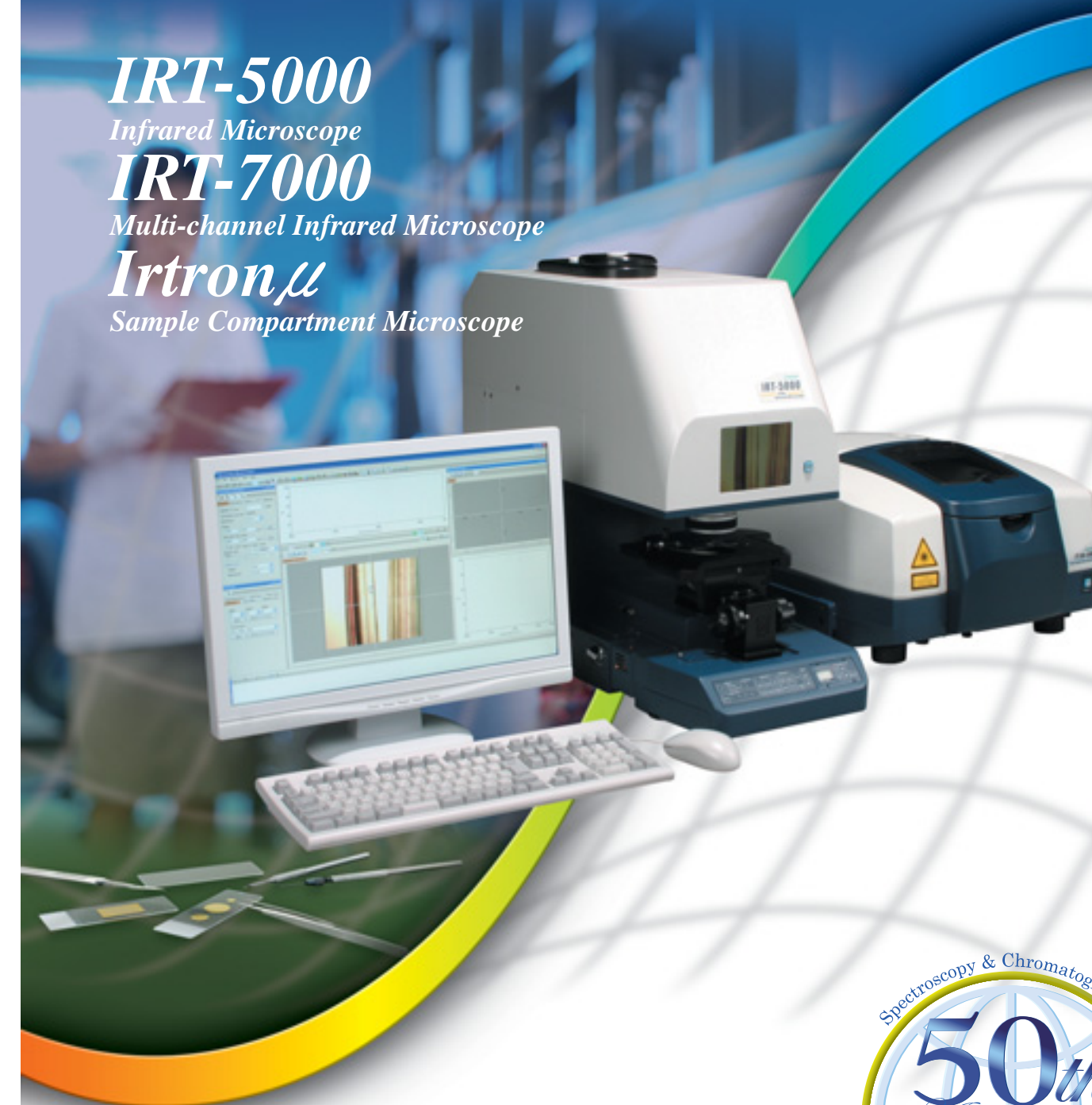
Infrared Microscope

IRT-7000

Multi-channel Infrared Microscope

Irtron μ

Sample Compartment Microscope



High performance
Ultimate flexibility
Exceptionally easy to use
Excellent image quality



JASCO FT-IR Microscopy and Imaging Systems



JASCO is proud to release two innovative FT-IR Microscope accessories, the IRT-5000 and IRT-7000, providing several new functions that drastically improve infrared micro-spectroscopy analyses. Both microscope systems can be easily interfaced with either the FT/IR-4000 or FT/IR-6000 spectrometer, offering the most advanced microscopy and imaging systems available in the market today. Coupling JASCO's proven technology for infrared spectroscopy (accumulated over 50 years) and with the most advanced optical design, the IRT-5000 and 7000 offer the best solution for even the most challenging sample analyses.

- High optical throughput
- Excellent signal to noise ratio
- High spatial resolution
- Operational flexibility
- Expandable capabilities
- Full range of accessories

Unparalleled performance, flexibility and ease of use

Next Generation FT-IR Microscopes

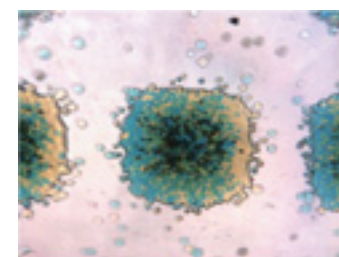


IRT-5000

Infrared Microscope

The IRT-5000 FT-IR Microscope employs a mid-band MCT detector as standard, while up to two detectors can be installed simultaneously. The standard "IQ Mapping" function allows multi-point, line, area and ATR mapping experiments without moving the sample stage, in addition to single-point measurements. An optional automatic X-Y-Z sample stage enables auto-focus and mapping analysis of large sample areas.

- IQ Mapping
- Dual detector capability
- Variety of measurement modes
(Transmission, reflection, ATR, Grazing Angle Reflectance)
- Multiple objective capabilities
- Field upgrade to IR Imaging
using a linear array detector



*Exceptional visual
observation quality*

A high-resolution CMOS video camera offers exceptional image quality in addition to a 3X optical zoom capability.

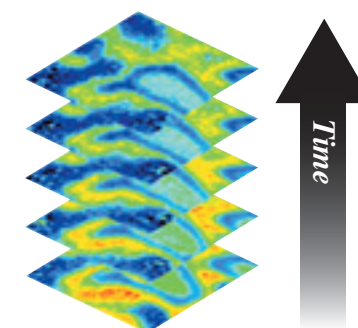


IRT-7000

Multi-channel IR Microscope

The IRT-7000 FT-IR multi-channel microscope offers two detectors as standard, a 16-channel linear array detector and a single-point MCT detector. The combination of the standard automatic sample stage and "IQ Mapping" function allows mapping analyses of a large sample area, multi-area ATR mapping, and IR imaging of a specific area with extremely high spatial resolution and excellent sensitivity in a short time.

- IQ Mapping
- Full IR Imaging function
- Up to four objectives
- Wide area mapping and multi-ATR imaging
- Dynamic Imaging with FT-IR step-scan option
- Multivariate analysis PCA
(Principal Component Analysis) (standard)

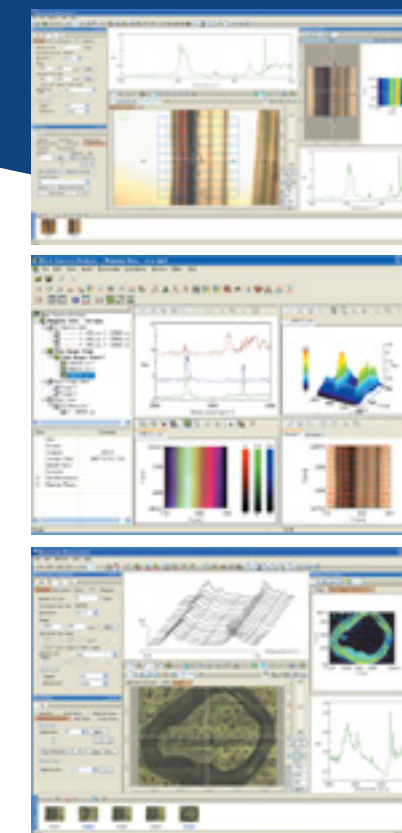


Dynamic Imaging

The world's first cross platform software

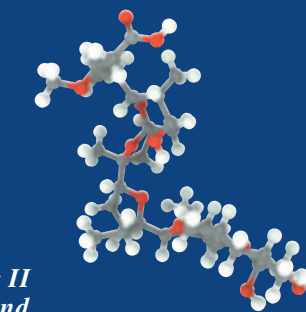
Spectra Manager™ II

Microscope interface



A full-featured software package, Spectra Manager II provides convenient, and/or automatic functions and simplified operational procedures to minimize manual operations. Powerful data processing functions include 2-D and/or 3-D visualization of chemical information with all standard manipulation of spectral data.

- Superior user-friendly graphical interface
- Auto-focus/Auto-illumination
- Registration of commonly used aperture settings
- Automatic recognition of microscope objectives
- Thumbnail display
(memorizing the sample position with focus and aperture information)
- Spectrum preview to check conditions before measurement
- IQ Monitoring for simultaneous observation of the spectrum and sample image
- Data storage linked with sample image and aperture information
- Report publishing capability (JASCO Canvas)



Expandability

A wide range of optional accessories is available. The microscope system can be optimized for sample application requirements.

- 5.7 inch TFT color display or Binocular
- Joystick for automated stage control
- Wavelength extension options
- ATR objectives and pressure sensor
- Grazing angle objective and IR polarizer
- Sample purge and vacuum options
- Sample observation options
(Visible polarizer; Fluorescence observation, Refractive objectives (10×, 20×), etc.)